THE MEASUREMENT, INSTRUMENTATION, AND SENSORS HANDBOOK

Editor-in-Chief

John G. Webster

CRC PRESS IEEE PRESS

A CRC Handbook Published in Cooperation with IEEE Press

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Electrical Engineering/Measurement and Instrumentation

THE
MEASUREMENT, INSTRUMENTATION, AND SENSORS
HANDBOOK

Editor-in-Chief

John G. Webster

The Measurement, Instrumentation, and Sensors Handbook describes the use of instruments and techniques for practical measurements required in engineering, physics, chemistry, and the life sciences.

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CRC Press Catalog No. 8347
IEEE Order Number: PC5771

ISBN 0-8493-8347-1
90000
9 780849 383472